

| | | | |
|-----------------------------------|---------------------------------------|---|-------------|
| Notice of References Cited | Application/Control No. 10/060,620 | Applicant(s)/Patent Under Reexamination COSSEL ET AL. | |
| | Examiner Shin-Hon Chen | Art Unit 2131 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------------|----------------|
| * | A | US-2003/0105849 | 06-2003 | Iwamoto et al. | 709/223 |
| * | B | US-2003/0081742 | 05-2003 | Czyszczeniowski et al. | 379/93.03 |
| * | C | US-6,880,091 | 04-2005 | Mattis et al. | 726/5 |
| * | D | US-6,446,204 | 09-2002 | Pang et al. | 713/153 |
| * | E | US-6,098,171 | 08-2000 | Johnson et al. | 726/16 |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.